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Search Notes				

Application/Control No.		Applicant(s)/Patent under Reexamination		
	10/698,945	LEE ET AL.		
	Examiner	Art Unit	_	
	James D. Ewart	2683		

SEARCHED					
Class	Subclass	Date	Examiner		
370	328	10/25/2005	JDE		
	329				
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/698,945	LEE ET AL.
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455	452.1	10/25/2005	JDE			
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